

Technical documentation



Support & training



CSD25481F4

SLPS420F - SEPTEMBER 2013 - REVISED FEBRUARY 2022

#### CSD25481F4 20 V P-Channel FemtoFET MOSFET

### 1 Features

- Ultra-low on resistance
- Ultra-low  $\mathsf{Q}_\mathsf{g}$  and  $\mathsf{Q}_\mathsf{gd}$
- High operating drain current
- Ultra-small footprint (0402 Case Size) – 1 mm × 0.6 mm
- Ultra-low profile
- 0.36 mm max height
- Integrated ESD protection diode
  - Rated >4 kV HBM
  - Rated >2 kV CDM
- Lead and halogen free
- **RoHS** compliant ٠

### 2 Applications

- Optimized for load switch applications
- Optimized for general purpose switching applications
- **Battery applications**
- Handheld and mobile applications

### **3 Description**

This 90-mΩ, 20-V P-Channel FemtoFET<sup>™</sup> MOSFET is designed and optimized to minimize the footprint in many handheld and mobile applications. This technology is capable of replacing standard small signal MOSFETs while providing at least a 60% reduction in footprint size.

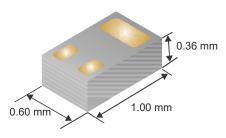


Figure 3-1. Typical Part Dimensions

#### **Product Summary**

T <sub>A</sub> = 25°	<b>2</b> °	TYPICAL VA	TYPICAL VALUE			
V <sub>DS</sub>	Drain-to-Source Voltage -20					
Qg	Gate Charge Total (-4.5 V)	913	913			
Q <sub>gd</sub>	Gate Charge Gate-to-Drain	153		рС		
R <sub>DS(on)</sub>		V <sub>GS</sub> = -1.8 V	395	mΩ		
	Drain-to-Source On-Resistance	V <sub>GS</sub> = -2.5 V	145	mΩ		
		V <sub>GS</sub> = -4.5 V	90	mΩ		
V <sub>GS(th)</sub>	Threshold Voltage	-0.95		V		

#### **Ordering Information**

U									
Device <sup>(1)</sup>	Qty	Media	Package	Ship					
CSD25481F4	3000	7-Inch Reel	Femto(0402)	Tape and					
CSD25481F4T	250	7-Inch Reel	Land Grid Array (LGA)	Reel					

(1) For all available packages, see the orderable addendum at the end of the data sheet.

T <sub>A</sub> = 25	T <sub>A</sub> = 25°C unless otherwise stated VALUE								
V <sub>DS</sub>	Drain-to-Source Voltage	-20	V						
V <sub>GS</sub>	Gate-to-Source Voltage	o-Source Voltage -12							
I <sub>D</sub>	Continuous Drain Current <sup>(1)</sup>	-2.5	А						
I <sub>DM</sub>	Pulsed Drain Current <sup>(2)</sup>	-13.1	Α						
I <sub>G</sub>	Continuous Gate Clamp Current	-35	mA						
	Pulsed Gate Clamp Current <sup>(2)</sup>	-350	mA						
PD	Power Dissipation <sup>(1)</sup>	500	mW						
V	Human Body Model (HBM)	4	kV						
V <sub>(ESD)</sub>	Charged Device Model (CDM)	2	kV						
T <sub>J</sub> , T <sub>stg</sub>	Operating Junction and Storage Temperature Range	–55 to 150	°C						

#### **Absolute Maximum Ratings**

- Typical  $R_{\theta JA} = 90^{\circ}$ C/W on 1 inch<sup>2</sup> (6.45 cm<sup>2</sup>), 2 oz. (1) (0.071 mm thick) Cu pad on a 0.06 inch (1.52 mm) thick FR4 PCB.
- Pulse duration  $\leq 100 \ \mu s$ , duty cycle  $\leq 1\%$ . (2)

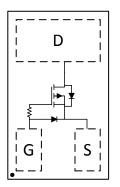


Figure 3-2. Top View





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### **4 Revision History**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision E (December 2017) to Revision F (February 2022)	Page
•	Changed ultra-low profile bullet from 0.35 mm to 0.36 mm in height	1
•	Updated ultra-low profile image height from 0.35 mm to 0.36 mm	1
•	Changed ultra-low profile image height from 0.35 mm to 0.36 mm	8
•	Added FemtoFET Surface Mount Guide note	9

C	hanges from Revision D (October 2014) to Revision E (December 2017)	Page
•	Changed the Pulsed Drain Current value From: -10 A To: -13.1 A in the Absolute Maximum Ratings tabl	e1
•	Changed Note 1 From: Typical R <sub>0JA</sub> = 85°C/W To: Typical R <sub>0JA</sub> = 90°C/W	1
•	Changed Note 2 From: Pulse duration $\leq$ 300 µs, duty cycle $\leq$ 2% To: Pulse duration $\leq$ 100 µs, duty cycle 1%	
•	Changed the typical R <sub>0.IA</sub> values in the <i>Thermal Information</i> table	3
•	Updated Figure 5-1.	4
	Updated Figure 5-10 with newly measured data.	
•	Updated all mechanical drawings, increased the size of the pads in the Section 7.3 section	<mark>8</mark>



# **5** Specifications

### **5.1 Electrical Characteristics**

(T<sub>A</sub> = 25°C unless otherwise stated)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
STATIC	CHARACTERISTICS					
BV <sub>DSS</sub>	Drain-to-Source Voltage	V <sub>GS</sub> = 0 V, I <sub>DS</sub> = -250 µA	-20			V
I <sub>DSS</sub>	Drain-to-Source Leakage Current	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = -16 V			-100	nA
I <sub>GSS</sub>	Gate-to-Source Leakage Current	$V_{DS} = 0 V, V_{GS} = -12 V$			-50	nA
V <sub>GS(th)</sub>	Gate-to-Source Threshold Voltage	$V_{DS} = V_{GS}, I_{DS} = -250 \ \mu A$	-0.7	-0.95	-1.2	V
		V <sub>GS</sub> = -1.8 V, I <sub>DS</sub> = -0.1 A		395	800	mΩ
Р	Drain-to-Source On-Resistance	$V_{GS} = -2.5 \text{ V}, I_{DS} = -0.5 \text{ A}$		145	174	mΩ
R <sub>DS(on)</sub>	Dram-to-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_{DS} = -0.5 \text{ A}$		90	105	mΩ
		V <sub>GS</sub> = -8 V, I <sub>DS</sub> = -0.5 A		75	88	mΩ
g <sub>fs</sub>	Transconductance	V <sub>DS</sub> = -10 V, I <sub>DS</sub> = -0.5 A		3.3		S
DYNAM	C CHARACTERISTICS					
C <sub>iss</sub>	Input Capacitance			189		pF
C <sub>oss</sub>	Output Capacitance	$V_{GS} = 0 V, V_{DS} = -10 V,$ f = 1 MHz		78		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			5.5		pF
R <sub>G</sub>	Series Gate Resistance			20		Ω
Qg	Gate Charge Total (4.5 V)			913		рС
Q <sub>gd</sub>	Gate Charge Gate-to-Drain	V <sub>DS</sub> = -10 V. I <sub>DS</sub> = -0.5 A		153		рС
Q <sub>gs</sub>	Gate Charge Gate-to-Source	$V_{\rm DS} = -10$ V, $I_{\rm DS} = -0.5$ A		240		рС
Q <sub>g(th)</sub>	Gate Charge at V <sub>th</sub>			116		рС
Q <sub>oss</sub>	Output Charge	V <sub>DS</sub> = -10 V, V <sub>GS</sub> = 0 V		1030		рС
t <sub>d(on)</sub>	Turn On Delay Time			4.1		ns
t <sub>r</sub>	Rise Time	V <sub>DS</sub> = -10 V, V <sub>GS</sub> = -4.5 V,		3.6		ns
t <sub>d(off)</sub>	Turn Off Delay Time	$I_{DS} = -0.5 \text{ A}, \text{R}_{\text{G}} = 2 \Omega$		16.9		ns
t <sub>f</sub>	Fall Time			6.7		ns
DIODE C	CHARACTERISTICS	· · · ·				
V <sub>SD</sub>	Diode Forward Voltage	I <sub>SD</sub> = -0.5 A, V <sub>GS</sub> = 0 V		-0.75		V
Q <sub>rr</sub>	Reverse Recovery Charge	V <sub>DS</sub> = -10 V, I <sub>F</sub> = -0.5 A, di/dt = 100 A/µs		1010		рС
t <sub>rr</sub>	Reverse Recovery Time	$V_{DS}$ = 10 V, $I_F$ = -0.5 A, $u_1/u_1$ = 100 A/µs		7.5		ns

#### **5.2 Thermal Information**

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$ 

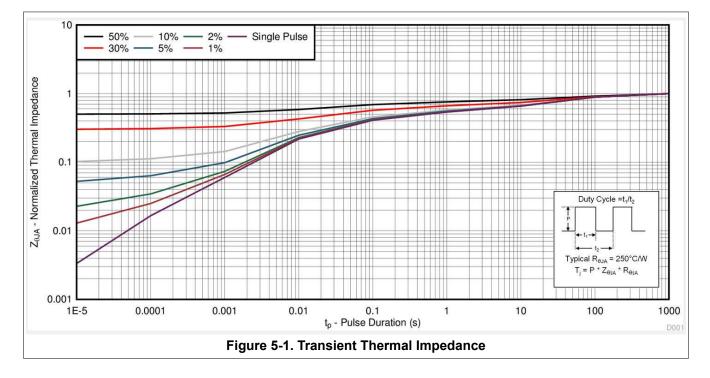
	THERMAL METRIC	TYPICAL VALUES	UNIT
Б	Junction-to-Ambient Thermal Resistance <sup>(1)</sup>	90	°C/W
R <sub>θJA</sub>	Junction-to-Ambient Thermal Resistance <sup>(2)</sup>	250	0/10

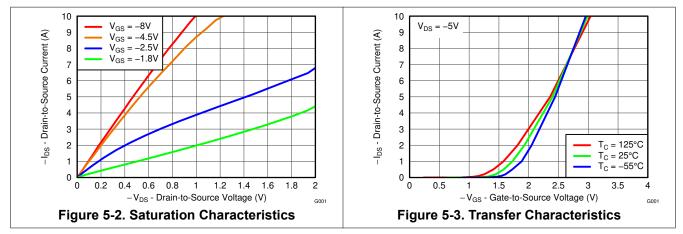
Device mounted on FR4 material with 1 inch<sup>2</sup> (6.45 cm<sup>2</sup>), 2 oz. (0.071 mm thick) Cu.
Device mounted on FR4 material with minimum Cu mounting area.



### **5.3 Typical MOSFET Characteristics**

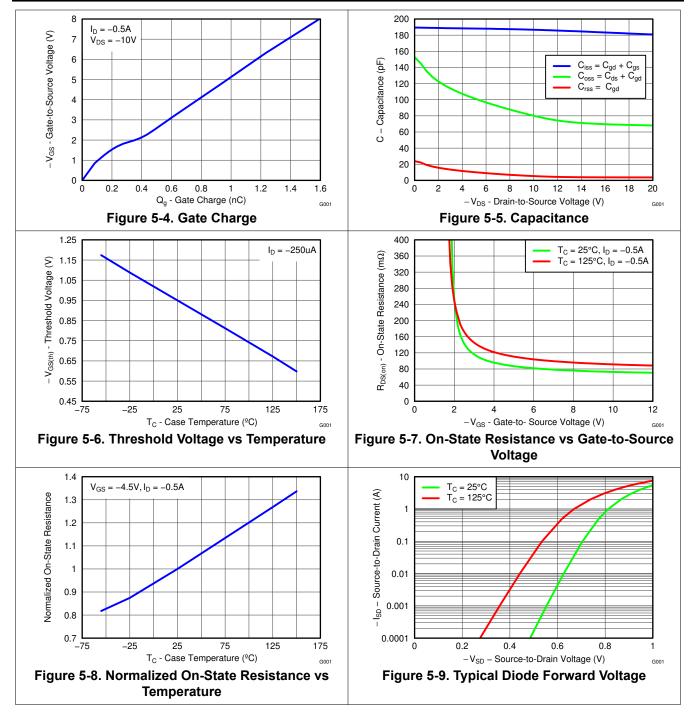
 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$ 





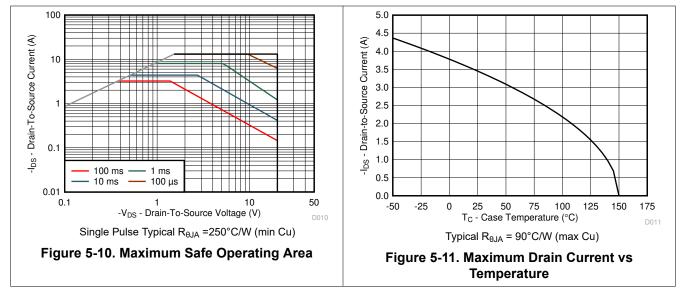


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### 6 Device and Documentation Support

#### 6.1 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 6.2 Trademarks

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TI E2E<sup>™</sup> are trademarks of Texas Instruments.

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#### 6.3 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 6.4 Glossary

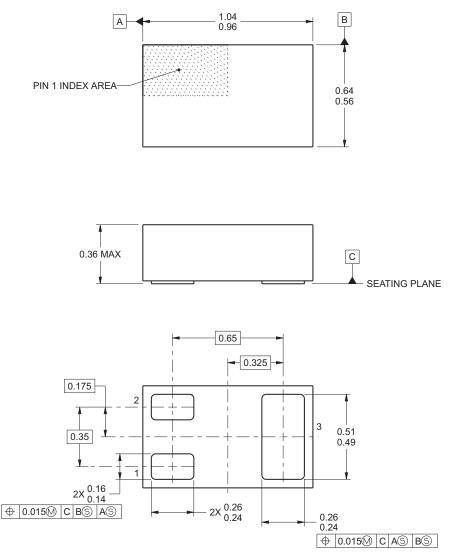
TI Glossary This glossary lists and explains terms, acronyms, and definitions.



### 7 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

#### 7.1 Mechanical Dimensions

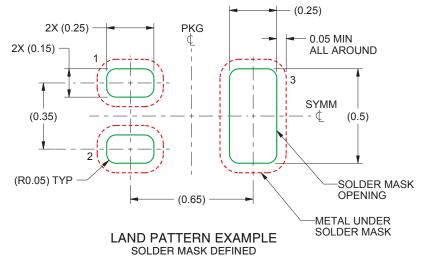


- A. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- B. This drawing is subject to change without notice.
- C. This package is a Pb-free bump design. Bump finish may vary. To determine the exact finish, refer to the device data sheet or contact a local TI representative.

Table 7-1. Pin Configuration								
Position Designation								
Pin 1	Gate							
Pin 2	Source							
Pin 3	Drain							

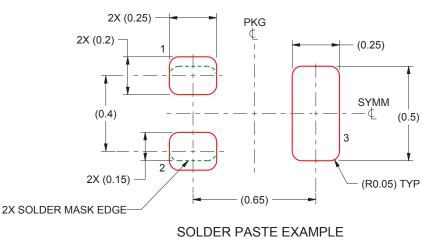


#### 7.2 Recommended Minimum PCB Layout



- A. All dimensions are in millimeters.
- B. For more information, see FemtoFET Surface Mount Guide (SLRA003D).

#### 7.3 Recommended Stencil Pattern



- A. All dimensions are in millimeters.
- B. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



#### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
CSD25481F4	ACTIVE	PICOSTAR	YJC	3	3000	RoHS & Green	NIAU	Level-1-260C-UNLIM	-55 to 150	CS	Samples
CSD25481F4T	ACTIVE	PICOSTAR	YJC	3	250	RoHS & Green	NIAU	Level-1-260C-UNLIM	-55 to 150	CS	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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11-Jan-2022

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